MountainsSPIP

Scientific analysis software package for Scanning Probe Microscopes

- Compatible with AFM, STM, SNOM through multichannel data file formats
- Prepare and clean-up measured data using powerful FFT tools
- Correct for scanner X-Y non-linearity, tip shape effect, noise, tilt and bow
- Analyze topography with texture and roughness parameters
- Analyze particles with shape and volume parameters, apply classifications
- Analyze nanomechanical properties with a complete force curve spectroscopy, including force-volume, Young's modulus, stiffness & energies calculation, WLC fitting…
- Analyze electrical properties with IV curve analysis, event detection and sorting
- Characterize lattice structures, patterns, periodic features and fibers
- Full automation features with statistical analysis
- Powerful reporting environment with multiple export formats
- For Windows 10/11 64-bit platforms

Applies to: material characterization, solar cells, semiconductors, MEMS, biotechs

Looking for: distributors, expertise

Contact: Mathieu Cognard

Information		
Force curve	1 / 4900	
Indentation parameters	I0	Unit
Young's modulus	23.4	MPa
Coefficient of determination R²	0.999	